Se	arch	Note	es

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/020,286	DABAGH ET AL.	
Examiner	Art Unit	
Yves Dalencourt	2157	

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	INTERFERENCE SEARCHED			
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WEST (updated text search)	11/26/2006	YD .
IEEE Xplore	11/26/2006	YD
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